**CLAIMS**

1. An inspection lighting device configured to irradiate inspection light onto an inspection object, the inspection lighting device comprising:

a surface light source for emitting inspection light;

a lens disposed between the surface light source and the inspection object and configured to form on the inspection object an irradiation solid angle of light that is emitted from the surface light source and irradiated onto the inspection object as the inspection light; and

a first filtering means disposed between the surface light source and the lens and in front of or behind a focus position of the lens, centered around the focus position, the first filtering means being configured to form a plurality of solid angle regions having different optical attributes as an irradiation solid angle of inspection light irradiated onto each point on the inspection object,

wherein a shape, a size, or an inclination of the solid angle regions, and an optical attribute such as a wavelength band, a polarization state, or a light amount can be set.

2. The inspection lighting device according to claim 1, further comprising:

at least one of a second shielding mask and a fourth filtering means at a position between the surface light source and the first filtering means and in the vicinity of a position at which the at least one of the second shielding mask and the fourth filtering means is imaged onto the inspection object by the lens,

wherein an irradiation area, an irradiation shape, an irradiation pattern, or an optical attribute of the inspection light irradiated onto the inspection object can be set as desired by using the second shielding mask or the fourth filtering means.

3. The inspection lighting device according to claim 1 or 2, further comprising:

a half mirror disposed between the lens and the inspection object in the inspection lighting device and configured to change an irradiation direction of the

inspection light and to transmit light from the inspection object so that the light can be imaged by the imaging device,

wherein optical axes of the solid angle regions as the irradiation solid angle of the inspection light at each point on the inspection object substantially coincide with an optical axis of the observation solid angle of the imaging device at that point on the inspection object.

4. The inspection lighting device according to any one of claims 1 to 3,

wherein the inspection lighting device is configured to be applied to an inspection system constituted by the inspection lighting device and an imaging device for imaging light reflected, transmitted, or scattered by the inspection object, and

with respect to an observation solid angle that is formed at each point on the inspection object when the imaging device images light from the inspection object, the shape, the size, or the inclination of the solid angle regions and the optical attribute contained in the solid angle regions can be set such that a desired change can be generated in a contrast at that point.

5. An inspection system comprising:

the inspection lighting device according to any one of claims 1 to 4; and

an imaging device for imaging light reflected, transmitted, or scattered by the inspection object,

wherein, in an irradiation solid angle of inspection light irradiated onto the inspection object by the inspection lighting device, a shape, a size, or an inclination of the solid angle regions at each point on the inspection object is set so as to be suitable for acquiring desired gradation information, based on a shape, a size, or an inclination of an observation solid angle of the imaging device at that point on the inspection object, or the shapes, the sizes, or the inclinations of the solid angle regions and the observation solid angle are set so as to be substantially uniform relative to each other.